Applicant(s)/Patent Under Reexamination ICHIHASHI ET AL. Examiner Thoi V Duong Applicant(s)/Patent Under Reexamination ICHIHASHI ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6344300 B1	02-2002	Baba et al.	430/7
	В	US-	(1)		
314	, C.	US-			
	D,	US-			
·	E	US-			
	F	US-			
	G	US-	· ·		
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U	US 2002/0085147 A1, Pub. Date July 4, 2002, Ko.				
	V					
	w					
	х					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.